



9th European Test Symposium

Congress Center, Ajaccio, Corsica, France
May 23 – 26, 2004



Call for Papers

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N. Toubia - U. of Texas (USA)

J. Tyszer - Poznan Tech. U. (PL)

Y. Zorian - Virage Logic (USA)

The IEEE European Test Symposium (ETS), formerly the European Test Workshop (ETW), is a well-recognized forum for presenting and discussing hot topics, trends, emerging results, and practical applications in the area of electronic-based device, board and system testing. The symposium will be co-sponsored by the IEEE Computer Society - Test Technology Technical Council (TTTC) and the LIRMM. We cordially invite you to participate and submit your contribution to ETS'04, which includes (but is not limited to) the following topics:

- Analog, Mixed-Signal, and RF Test
- ATE Hardware and Software
- ATPG and High-Level TPG
- On-Line and Off-Line BIST
- Debug and Diagnosis
- Test of MCMS and Boards
- Design Verification/Validation
- Emerging Testability Standards
- Signal Integrity Test
- Fault Simulation
- FPGA Test
- High-Level DfT
- Low-Cost Testers
- Thermal Testing
- MEMS Testing
- Current based testing
- Power issues in testing
- System Test
- Self-Repair Methodologies
- Failure Analysis, Defect and Fault Modeling
- Scan-Based Techniques and Boundary Scan
- Test of Embedded Cores and System-on-Chip
- Defect/Fault Tolerance and Reliability
- Test Resource Partitioning and Embedded Test
- Test Synthesis and Synthesis for Testability
- Memory and Processor Test
- Yield Analysis and Enhancement

Submissions

ETS'04 seeks several types of contributions, including *Research Contributions*, *Application Contributions*, *Emerging Ideas Contributions*, *PhD student Contributions*. Review criteria and publication policy are posted at www.lirmm.fr/ETS/ETS04. We recommend prospective authors to visit this web site because of the new publication policy due to the new format of the event. Electronic submission of PDF files via www.lirmm.fr/ETS/ETS04 is required.

Proceedings

The IEEE Computer Society will publish formal *proceedings* of the symposium papers. However, due to the unique format of the event enabling informal presentations (see web site), an informal *digest* of these presentations will be distributed at the symposium. The best contributions will be selected for submission to regular issues of the *Journal of Electronic Testing: Theory and Applications* (JETTA), published by Kluwer Academic Publishers.

Tutorials

IEEE TTTC Test Technology Educational Program (TTEP) 2004 tutorials will be offered during May 23 on emerging test technology topics. Tutorial proposals should be submitted according to the guidelines at <http://tab.computer.org/ttcc/teg/ttep>.

Deadlines

- Submission deadline: **February 1st, 2004**
- Notification of acceptance: **March 24th, 2004**
- Camera ready: **April 18th, 2004**

Further Information

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The 2004 edition of the symposium will take place in the beautiful city of Ajaccio. Corsica is a wonderfully enigmatic country. Its attraction lies in nature, sun, and sea, not in artifact. It is a rock-hard fragile paradise. Its poets and singers are nearest to revealing its secrets.

Organizing Committee

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